

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceed the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
 - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

74F545

Octal Bidirectional Transceiver with 3-STATE Outputs

General Description

The 74F545 is an 8-bit, 3-STATE, high-speed transceiver. It provides bidirectional drive for bus-oriented microprocessor and digital communications systems. Straight through bidirectional transceivers are featured, with 24 mA bus drive capability on the A Ports and 64 mA bus drive capability on the B Ports.

One input, Transmit/Receive (T/\bar{R}) determines the direction of logic signals through the bidirectional transceiver. Transmit enables data from A-to-B Ports; Receive enables data from B-to-A Ports. The Output Enable input disables both A and B Ports by placing them in a 3-STATE condition.

Features

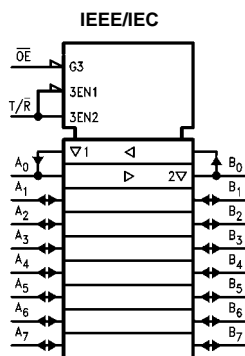
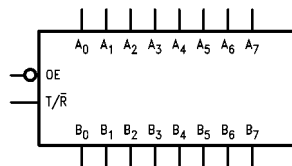
- Higher drive than 8304
- 8-bit bidirectional data flow reduces system package count
- 3-STATE inputs/outputs for interfacing with bus-oriented systems
- 24 mA and 64 mA bus drive capability on A and B Ports, respectively
- Transmit/Receive and Output Enable simplify control logic
- Guaranteed 4000V minimum ESD protection

Ordering Code:

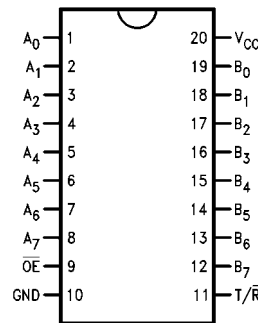
Order Number	Package Number	Package Description
74F545SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F545SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F545PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

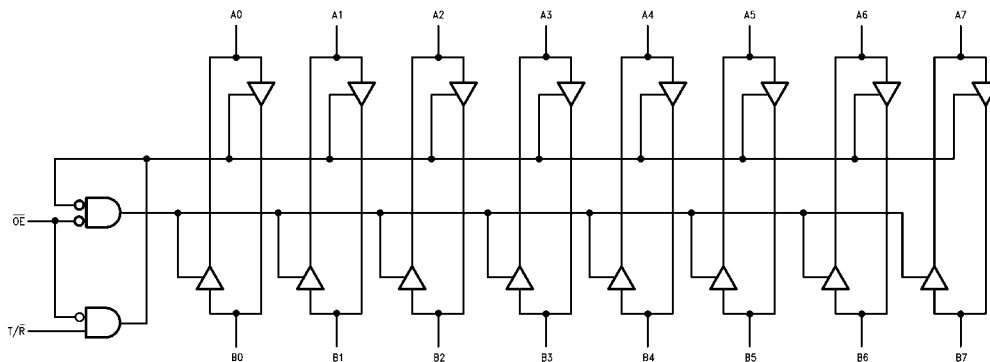
Pin Names	Description	U.L. HIGH/LOW	Input I_{IH}/I_{IL} Output I_{OH}/I_{OL}
\overline{OE}	Output Enable Input (Active LOW)	1.0/2.0	20 μ A/-1.2 mA
$\overline{T/R}$	Transmit/Receive Input	1.0/2.0	20 μ A/-1.2 mA
A_0 - A_7	Side A 3-STATE Inputs or 3-STATE Outputs	3.5/1.083 150/40 (33.3)	70 μ A/-650 μ A -3 mA/24 mA (20 mA)
B_0 - B_7	Side B 3-STATE Inputs or 3-STATE Outputs	3.5/1.083 600/106.6 (80)	70 μ A/-650 μ A -12 mA/64 mA (48 mA)

Truth Table

Inputs		Outputs
\overline{OE}	$\overline{T/R}$	
L	L	Bus B Data to Bus A
L	H	Bus A Data to Bus B
H	X	High Z

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial
Z = High Impedance

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	-55°C to +125°C
Junction Temperature under Bias	-55°C to +150°C
V _{CC} Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Output in HIGH State (with V _{CC} = 0V)	
Standard Output	-0.5V to V _{CC}
3-STATE Output	-0.5V to +5.5V
Current Applied to Output in LOW State (Max)	twice the rated I _{OL} (mA)
ESD Last Passing Voltage (Min)	4000V

Recommended Operating Conditions

Free Air Ambient Temperature	0°C to +70°C
Supply Voltage	+4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

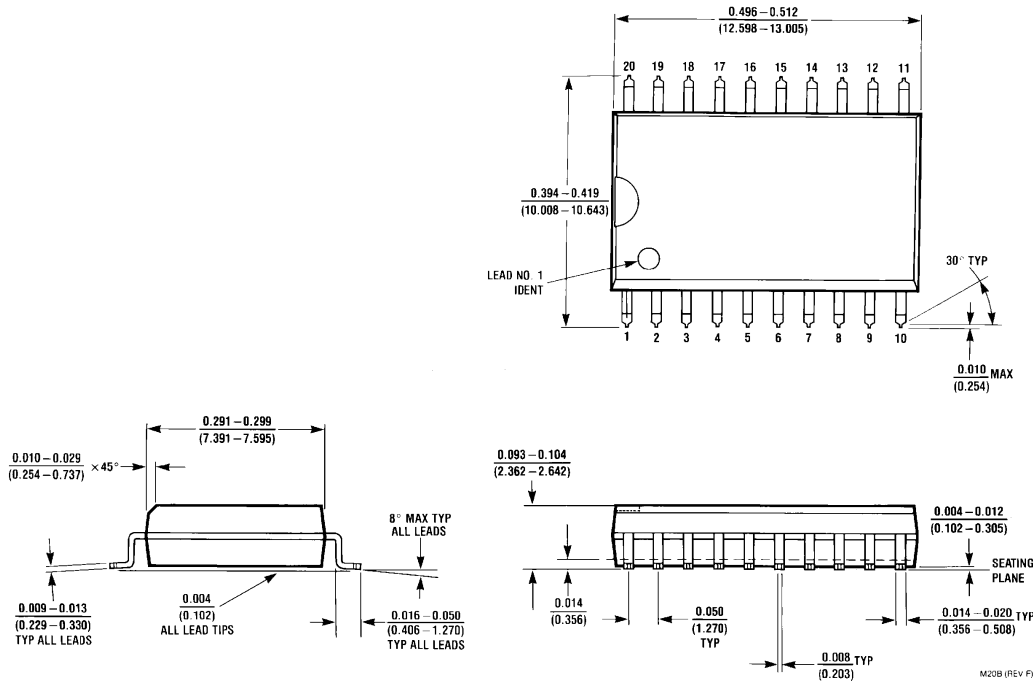
DC Electrical Characteristics

Symbol	Parameter	Min	Typ	Max	Units	V _{CC}	Conditions
V _{IH}	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage			0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	I _{IN} = -18 mA (\overline{OE} , \overline{TR})
V _{OH}	Output HIGH Voltage	10% V _{CC} 10% V _{CC} 10% V _{CC} 5% V _{CC} 5% V _{CC}	2.5 2.4 2.0 2.7 2.7		V	Min	I _{OH} = -1 mA (A _n) I _{OH} = -3 mA (A _n) I _{OH} = -15 mA (B _n) I _{OH} = -1 mA (A _n) I _{OH} = -3 mA (A _n)
V _{OL}	Output LOW Voltage	10% V _{CC} 10% V _{CC}		0.5 0.55	V	Min	I _{OL} = 24 mA (A _n) I _{OL} = 64 mA (B _n)
I _{IH}	Input HIGH Current			5.0	μA	Max	V _{IN} = 2.7V (\overline{OE} , \overline{TR})
I _{BVI}	Input HIGH Current Breakdown Test			7.0	μA	Max	V _{IN} = 7.0V (\overline{OE} , \overline{TR})
I _{BVIT}	Input HIGH Current Breakdown (I/O)			0.5	mA	Max	V _{IN} = 5.5V (A _n , B _n)
I _{CEx}	Output HIGH Leakage Current			50	μA	Max	V _{OUT} = V _{CC}
V _{ID}	Input Leakage Test	4.75			V	0.0	I _{ID} = 1.9 μA All Other Pins Grounded
I _{OD}	Output Leakage Circuit Current			3.75	μA	0.0	V _{IOD} = 150 mV All Other Pins Grounded
I _{IL}	Input LOW Current			-1.2	mA	Max	V _{IN} = 0.5V (\overline{OE} , \overline{TR})
I _{IH} + I _{OZH}	Output Leakage Current			70	μA	Max	V _{OUT} = 2.7V (A _n , B _n)
I _{IL} + I _{OZL}	Output Leakage Current			-650	μA	Max	V _{OUT} = 0.5V (A _n , B _n)
I _{OS}	Output Short-Circuit Current	-60 -100		-150 -225	mA	Max	V _{OUT} = 0V (A _n) V _{OUT} = 0V (B _n)
I _{ZZ}	Bus Drainage Test			500	μA	0.0V	V _{OUT} = 5.25V
I _{CCH}	Power Supply Current		70	90	mA	Max	V _O = HIGH
I _{CCL}	Power Supply Current		95	120	mA	Max	V _O = LOW
I _{CCZ}	Power Supply Current		85	110	mA	Max	V _O = HIGH Z

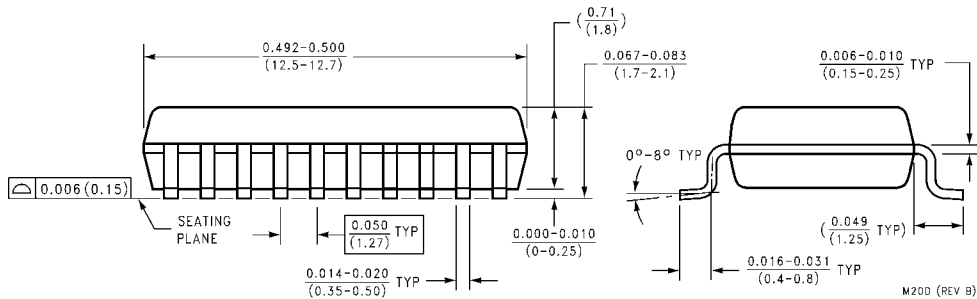
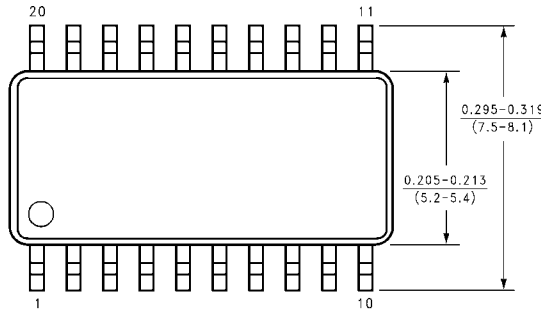
AC Electrical Characteristics

Symbol	Parameter	T _A = +25°C V _{CC} = +5.0V C _L = 50 pF			T _A = -55°C to +125°C V _{CC} = +5.0V C _L = 50 pF		T _A = 0°C to +70°C V _{CC} = +5.0V C _L = 50 pF		Units
		Min	Typ	Max	Min	Max	Min	Max	
t _{PLH}	Propagation Delay	2.5	4.2	6.0	2.0	7.5	2.5	7.0	ns
t _{PHL}	A _n to B _n or B _n to A _n	2.5	4.6	6.0	2.0	7.5	2.5	7.0	
t _{PZH}	Output Enable Time	3.0	5.3	7.0	2.5	9.0	3.0	8.0	ns
t _{PZL}		3.5	6.0	8.0	3.0	10.0	3.5	9.0	
t _{PHZ}	Output Disable Time	3.0	5.0	6.5	2.5	9.0	3.0	7.5	
t _{PLZ}		2.0	5.0	6.5	2.0	10.0	2.0	7.5	

Physical Dimensions inches (millimeters) unless otherwise noted

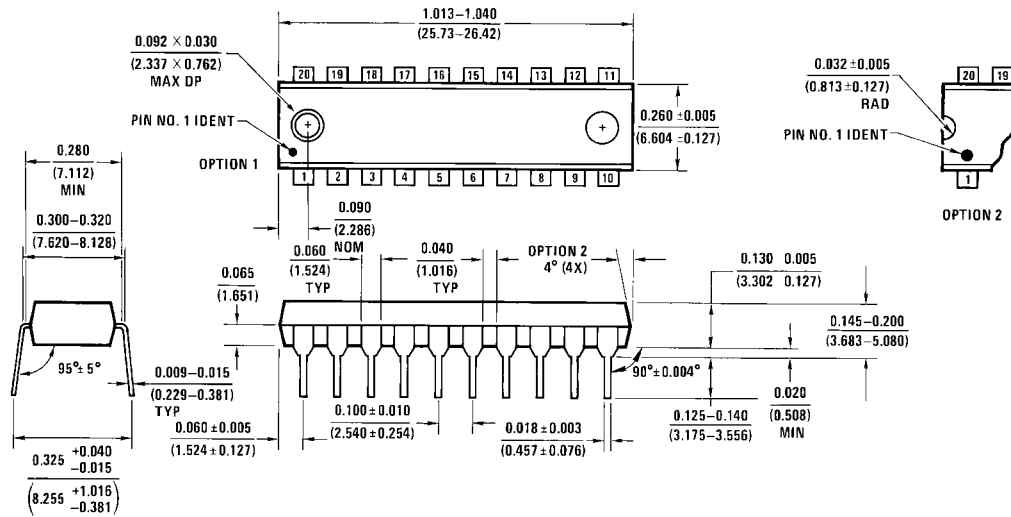


**20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
Package Number M20B**



**20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
Package Number M20D**

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



**20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide
Package Number N20A**

N20A (REV G)

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